

Notice of References Cited	Application/Control No. 10/791,132	Applicant(s)/Patent Under Reexamination HOPKINS ET AL.	
	Examiner Elias Desta	Art Unit 2857	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2003/0042861	03-2003	Schwartz et al.	318/434
	C	US-6,393,373	05-2002	Duyar et al.	702/115
	D	US-6,262,550	07-2001	Kliman et al.	318/565
	E	US-6,671,818	12-2003	Mikurak, Michael G.	714/4
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NON-PATENT DOCUMENTS

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	U	Schaik et al., 'Conditon Based Maintenance on MV Cable Circuits as Part of Asset Management Philosophy, Diagnostic Methods, Experiences, Results and the Future', June 2001, IEEE Artile, No. 482, pages 1-5
	V	James et al., 'Development of Computer-Based Measurements and their Applications to PD Pattern Analysis', October 1995, IEEE Article, Vol. 2, No. 5, pages 838-856
	W	Ison et al., 'Fault Diagnosis of Plasma Etch Equipment', June 1998, Berkeley University, pages 1-4
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.